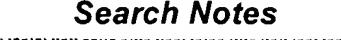


Search Notes 	Application/Control No. 10/628,327	Applicant(s)/Patent under Reexamination IIDA, TAKAYUKI
	Examiner Nhan T. Tran	Art Unit 2622

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner